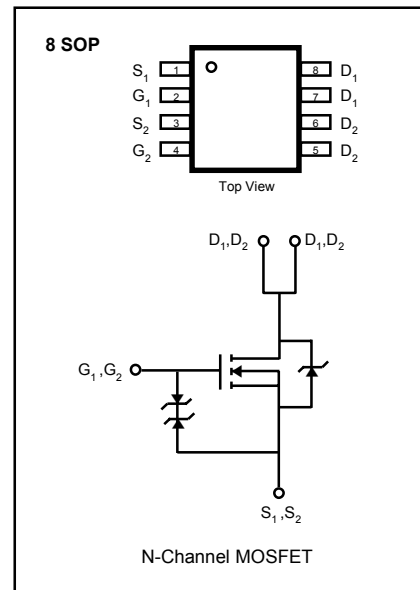


## FEATURES

- ❑ Extremely Lower  $R_{DS(ON)}$
- ❑ Improved Inductive Ruggedness
- ❑ Fast Switching Times
- ❑ Rugged Polysilicon Gate Cell Structure
- ❑ Low Input Capacitance
- ❑ Extended Safe Operating Area
- ❑ Improved High Temperature Reliability
- ❑ Surface Mounting Package : **8SOP**



## Absolute Maximum Ratings

| Symbol         | Characteristic                                                           | Value        | Units      |
|----------------|--------------------------------------------------------------------------|--------------|------------|
| $V_{DSS}$      | Drain-to-Source Voltage(1)                                               | 50           | V          |
| $V_{DGR}$      | Drain-Gate Voltage( $R_{GS}=1.0M\Omega$ )(1)                             | 50           | V          |
| $V_{GS}$       | Gate-to-Source Voltage                                                   | $\pm 20$     | V          |
| $I_D$          | Continuous Drain Current $T_A=25^\circ C$                                | 2.0          | A          |
| $I_D$          | Continuous Drain Current $T_A=100^\circ C$                               | 1.6          | A          |
| $I_{DM}$       | Drain Current-Pulsed (2)                                                 | 8.0          | V          |
| $P_D$          | Total Power Dissipation $T_A=25^\circ C$                                 | 2.0          | W          |
|                | $T_A=70^\circ C$                                                         | 1.3          |            |
| $T_J, T_{STG}$ | Operating and Storage Junction Temperature Range                         | - 55 to +150 | $^\circ C$ |
| $T_L$          | Maximum Lead Temp. for Soldering Purposes, 1/16" from case for 5 seconds | 300          |            |

## Notes ;

(1)  $T_J=25^\circ C$  to  $150^\circ C$ 

(2) Repetitive Rating : Pulse Width Limited by Max. Junction Temperature

**Electrical Characteristics** ( $T_A=25^\circ\text{C}$  unless otherwise specified)

| Symbol       | Characteristic                   | Min. | Typ. | Max. | Units    | Test Condition                              |
|--------------|----------------------------------|------|------|------|----------|---------------------------------------------|
| $BV_{DSS}$   | Drain-Source Breakdown Voltage   | 50   | --   | --   | V        | $V_{GS}=0V, I_D=250\mu A$                   |
| $V_{GS(th)}$ | Gate Threshold Voltage           | 2.0  | --   | 4.0  | V        | $V_{DS}=V_{GS}, I_D=250\mu A$               |
| $I_{GSS}$    | Gate-Source Leakage, Forward     | --   | --   | 1.0  | $\mu A$  | $V_{GS}=20V$                                |
|              | Gate-Source Leakage, Reverse     | --   | --   | -1.0 | $\mu A$  | $V_{GS}=-20V$                               |
| $I_{DSS}$    | Drain-to-Source Leakage Current  | --   | --   | 2    | $\mu A$  | $V_{DS}=50V$                                |
|              |                                  | --   | --   | 25   |          | $V_{DS}=40V, T_J=55^\circ\text{C}$          |
| $I_{DON}$    | On-State Drain-Source Current(2) | 8.0  | --   | --   | A        | $V_{GS}=10V, V_{DS}=5V$                     |
| $R_{DS(on)}$ | Static Drain-Source              |      |      | 0.3  | $\Omega$ | $V_{GS}=10V, I_D=1.5A$                      |
|              | On-State Resistance(2)           |      |      | 0.5  |          | $V_{GS}=5.0V, I_D=0.6A$                     |
| $g_{fs}$     | Forward Transconductance         | --   | 2.5  | --   | S        | $V_{DS} \geq 15V, I_D=2.0A$                 |
| $t_{d(on)}$  | Turn-On Delay Time               | --   | --   | 40   | ns       | $V_{DD}=30V, I_D=0.6A,$<br>$Z_0=6.0\Omega,$ |
| $t_r$        | Rise Time                        | --   | --   | 70   |          |                                             |
| $t_{d(off)}$ | Turn-Off Delay Time              | --   | --   | 100  |          |                                             |
| $t_f$        | Fall Time                        | --   | --   | 70   |          |                                             |
| $Q_g$        | Total Gate Charge                | --   | --   | 15   | nC       | $V_{DS}=25V, V_{GS}=10V,$<br>$I_D=1.3A$     |
| $Q_{gs}$     | Gate-Source Charge               | --   | 1.0  | --   |          |                                             |
| $Q_{gd}$     | Gate-Drain ("Miller") Charge     | --   | 2.0  | --   |          |                                             |

**Thermal Resistance**

| Symbol          | Characteristic      | Typ. | Max. | Units              |
|-----------------|---------------------|------|------|--------------------|
| $R_{\theta JA}$ | Junction-to-Ambient | --   | 62.5 | $^\circ\text{C/W}$ |

**Notes ;**

- (1)  $T_J=25^\circ\text{C}$  to  $150^\circ\text{C}$   
 (2) Pulse Test : Pulse Width  $\leq 300\mu s$ , Duty Cycle  $\leq 2\%$

**Source-Drain Diode Ratings and Characteristics**

| Symbol   | Characteristic                            | Min. | Typ. | Max. | Units | Test Condition                                                                   |
|----------|-------------------------------------------|------|------|------|-------|----------------------------------------------------------------------------------|
| $I_S$    | Continuous Source Current<br>(Body Diode) | --   | --   | 1.8  | A     | Modified MOSFET Symbol<br>Showing the Integral Reverse<br>P-N Junction Rectifier |
| $V_{SD}$ | Diode Forward Voltage(2)                  | --   | --   | 1.2  | V     | $T_J=25^\circ\text{C}, I_S=1.25A, V_{GS}=0V$                                     |
| $t_{rr}$ | Reverse Recovery Time                     | --   | --   | 100  | ns    | $T_J=25^\circ\text{C}, I_F=2.5A, di_F/dt=100A/\mu s$                             |

Fig 1. Output Characteristics

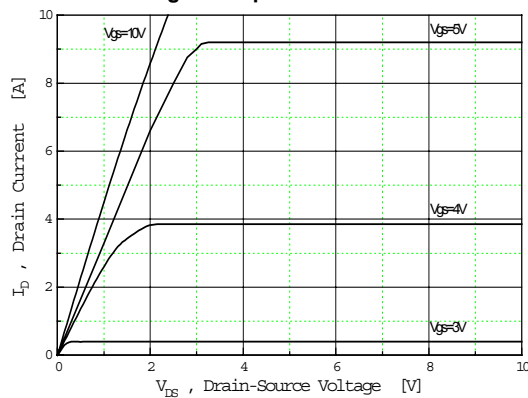


Fig 2. Transfer Characteristics

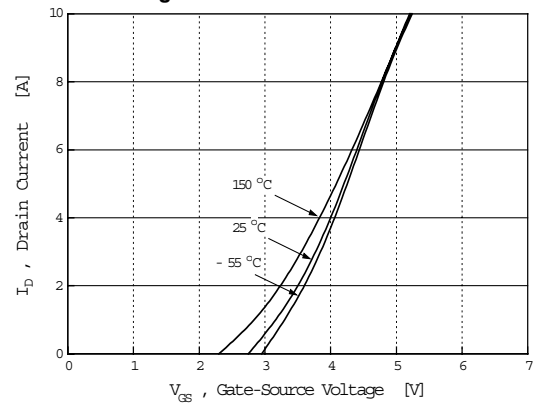


Fig 3. On-Resistance vs. Drain Current

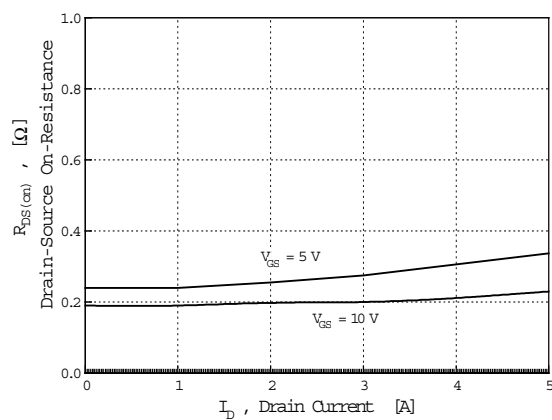


Fig 4. Capacitance vs. Drain-Source Voltage

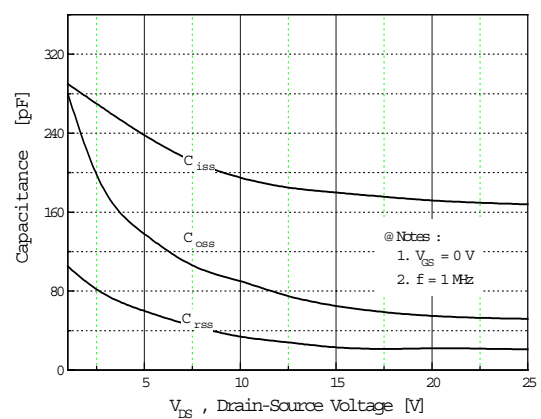


Fig 5. Breakdown Voltage vs. Temperature

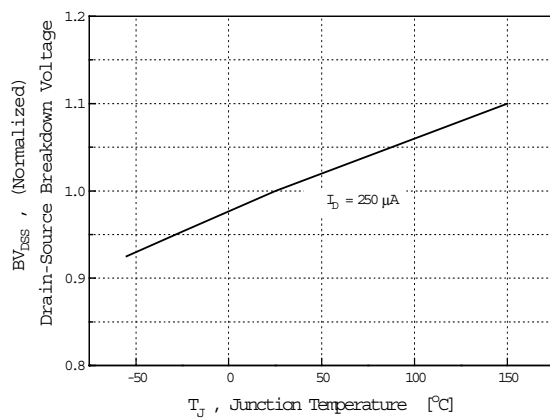


Fig 6. Normalized On-Resistance vs. Temperature

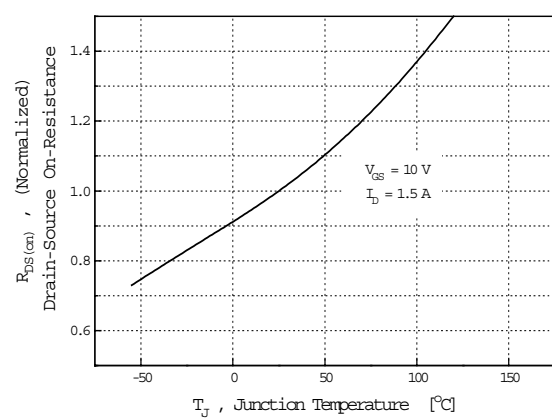


Fig 7. Normalized Effective Transient Thermal Impedance, Junction-to-Ambient

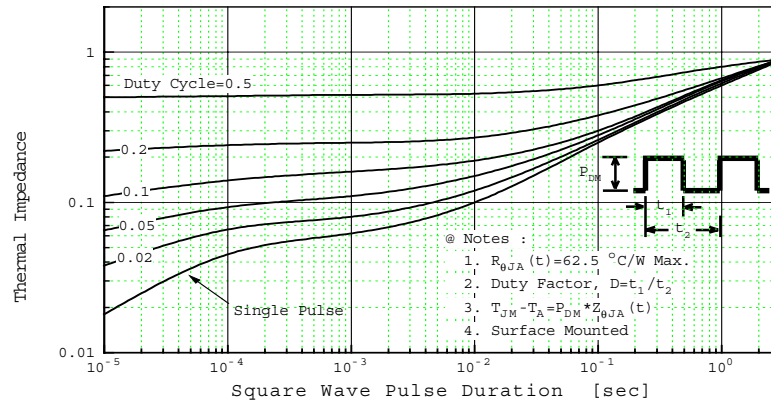


Fig 8. Source-Drain Diode Forward Voltage

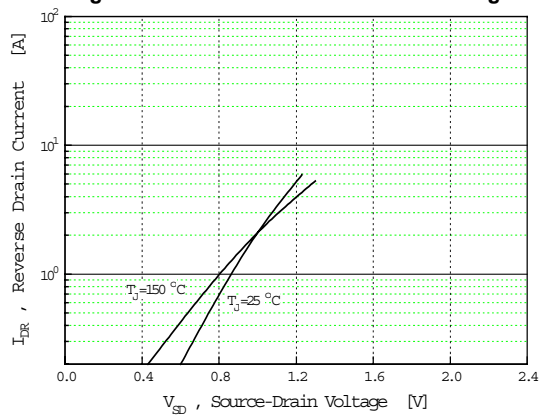


Fig 9. Gate Charge vs. Gate-Source Voltage

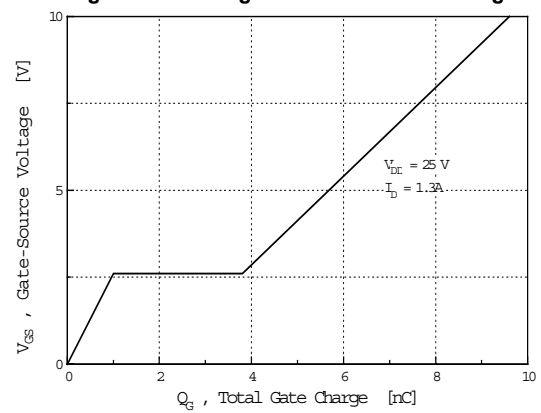
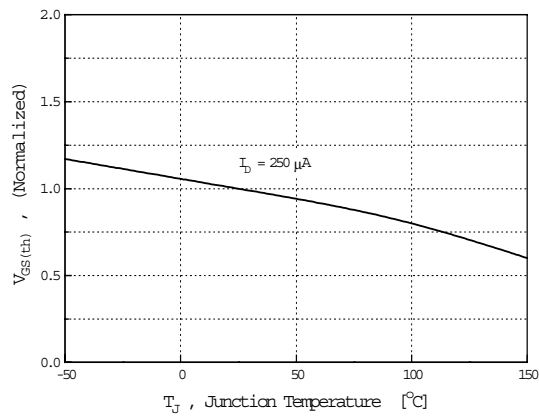


Fig 10. Threshold Voltage



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| Bottomless™                          | FPS™                | MICROCOUPLER™ | QFET®               | TinyLogic®      |
| Build it Now™                        | FRFET™              | MicroFET™     | QS™                 | TINYOPTO™       |
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| E²CMOS™                              | i-Lo™               | OCX™          | µSerDes™            | VCX™            |
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| Programmable Active Droop™           |                     | Power247™     | SuperSOT™-3         |                 |
|                                      |                     | PowerEdge™    | SuperSOT™-6         |                 |

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